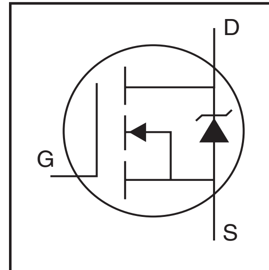
International
IOR Rectifier

IRFP150V

HEXFET® Power MOSFET

- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated



V_{DSS} = 100V

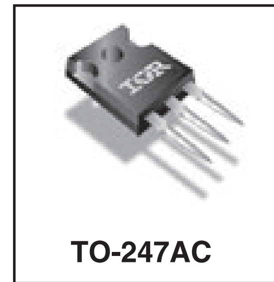
$R_{DS(on)}$ = 24mΩ

I_D = 47A

Description

Advanced HEXFET® Power MOSFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-247 package is preferred for commercial-industrial applications where higher power levels preclude the use of TO-220 devices. The TO-247 is similar but superior to the earlier TO-218 packcage because of its isolated mounting hole.



TO-247AC

Absolute Maximum Ratings

	Parameter	Max.	Units
I_D @ T_C = 25°C	Continuous Drain Current, V_{GS} @ 10V	46	A
I_D @ T_C = 100°C	Continuous Drain Current, V_{GS} @ 10V	32	
I_{DM}	Pulsed Drain Current ①	230	
P_D @T_C = 25°C	Power Dissipation	140	W
	Linear Derating Factor	0.91	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
I_{AR}	Avalanche Current①	28	A
E_{AR}	Repetitive Avalanche Energy①	20	mJ
dv/dt	Peak Diode Recovery dv/dt ③	5.8	V/ns
T_J T_{STG}	Operating Junction and Storage Temperature Range	-55 to + 175	°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torque, 6-32 or M3 srew	10 lbf•in (1.1N•m)	

Thermal Resistance

	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	——	1.1	°C/W
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.24	——	
$R_{\theta JA}$	Junction-to-Ambient	——	40	

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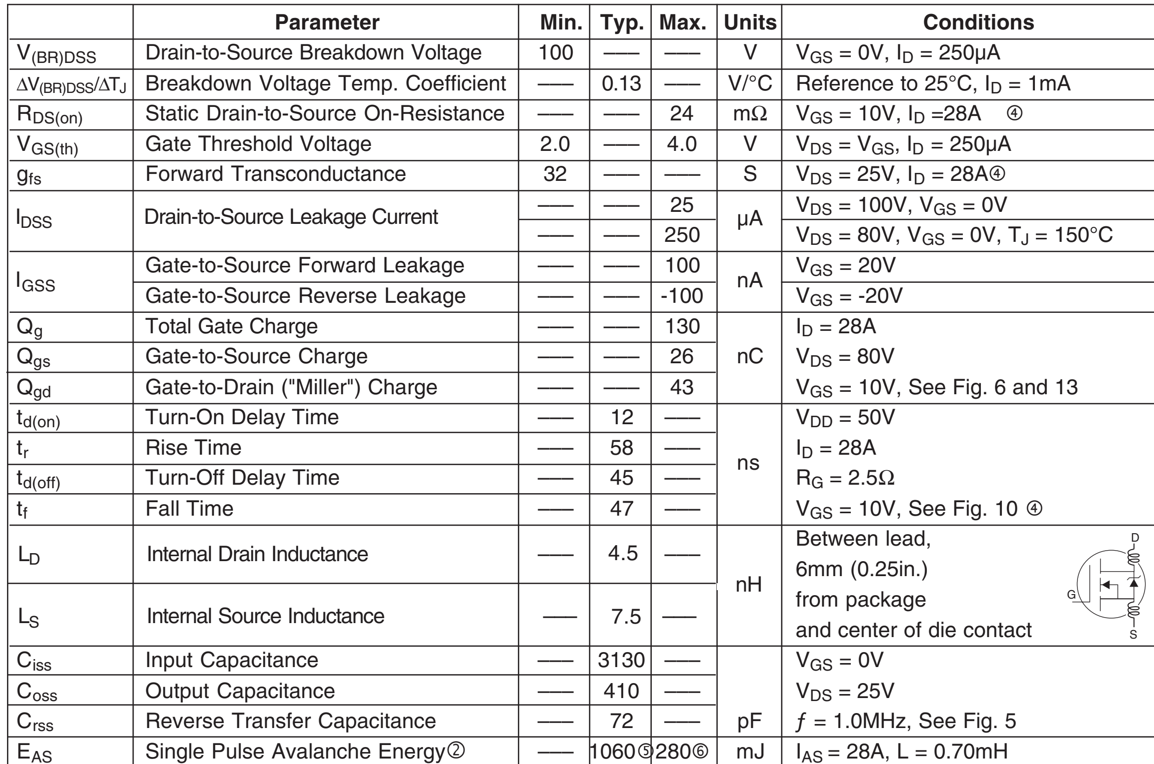
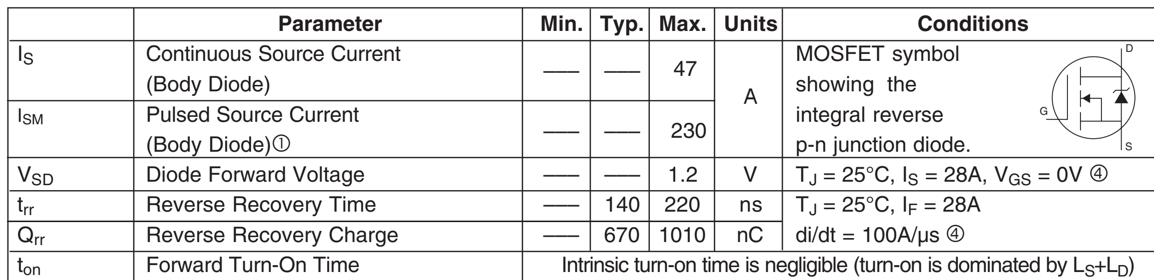
Electrical Characteristics @ T_J = 25°C (unless otherwise specified)



	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	100	—	—	V	V_{GS} = 0V, I_D = 250μA
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.13	—	V/°C	Reference to 25°C, I_D = 1mA
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	—	—	24	mΩ	V_{GS} = 10V, I_D =28A ④
$V_{GS(th)}$	Gate Threshold Voltage	2.0	—	4.0	V	V_{DS} = V_{GS}, I_D = 250μA
g_{fs}	Forward Transconductance	32	—	—	S	V_{DS} = 25V, I_D = 28A④
I_{DSS}	Drain-to-Source Leakage Current	—	—	25	μA	V_{DS} = 100V, V_{GS} = 0V
		—	—	250		V_{DS} = 80V, V_{GS} = 0V, T_J = 150°C
I_{GSS}	Gate-to-Source Forward Leakage	—	—	100	nA	V_{GS} = 20V
	Gate-to-Source Reverse Leakage	—	—	-100		V_{GS} = -20V
Q_g	Total Gate Charge	—	—	130	nC	I_D = 28A
Q_{gs}	Gate-to-Source Charge	—	—	26		V_{DS} = 80V
Q_{gd}	Gate-to-Drain ("Miller") Charge	—	—	43		V_{GS} = 10V, See Fig. 6 and 13
$t_{d(on)}$	Turn-On Delay Time	—	12	—	ns	V_{DD} = 50V
t_r	Rise Time	—	58	—		I_D = 28A
$t_{d(off)}$	Turn-Off Delay Time	—	45	—		R_G = 2.5Ω
t_f	Fall Time	—	47	—		V_{GS} = 10V, See Fig. 10 ④
L_D	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6mm (0.25in.)
L_S	Internal Source Inductance	—	7.5	—		from package and center of die contact
C_{iss}	Input Capacitance	—	3130	—	pF	V_{GS} = 0V
C_{oss}	Output Capacitance	—	410	—		V_{DS} = 25V
C_{rss}	Reverse Transfer Capacitance	—	72	—		f = 1.0MHz, See Fig. 5
E_{AS}	Single Pulse Avalanche Energy②	—	1060⑤	280⑥	mJ	I_{AS} = 28A, L = 0.70mH

Source-Drain Ratings and Characteristics



	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	47	A	MOSFET symbol showing the
I_{SM}	Pulsed Source Current (Body Diode)①	—	—	230		integral reverse p-n junction diode.
V_{SD}	Diode Forward Voltage	—	—	1.2	V	T_J = 25°C, I_S = 28A, V_{GS} = 0V ④
t_{rr}	Reverse Recovery Time	—	140	220	ns	T_J = 25°C, I_F = 28A
Q_{rr}	Reverse Recovery Charge	—	670	1010	nC	di/dt = 100A/μs ④
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L_S+L_D)				

Notes:

① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11).

② Starting T_J = 25°C, L = 0.70mH, R_G = 25Ω, I_{AS} = 28A, V_{GS}=10V (See Figure 12).

③ $I_{SD} \le$ 28A, di/dt $\le$ 380A/μs, $V_{DD} \le V_{(BR)DSS}$, $T_J \le$ 175°C.

④ Pulse width $\le$ 400μs; duty cycle $\le$ 2%.

⑤ This is a typical value at device destruction and represents operation outside rated limits.

⑥ This is a calculated value limited to T_J = 175°C .

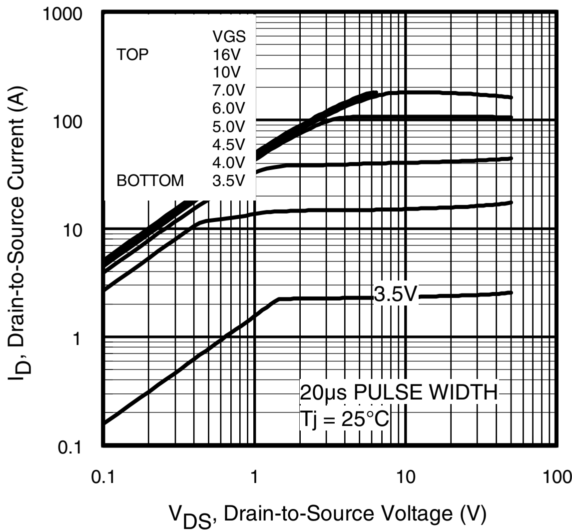


Fig 1. Typical Output Characteristics

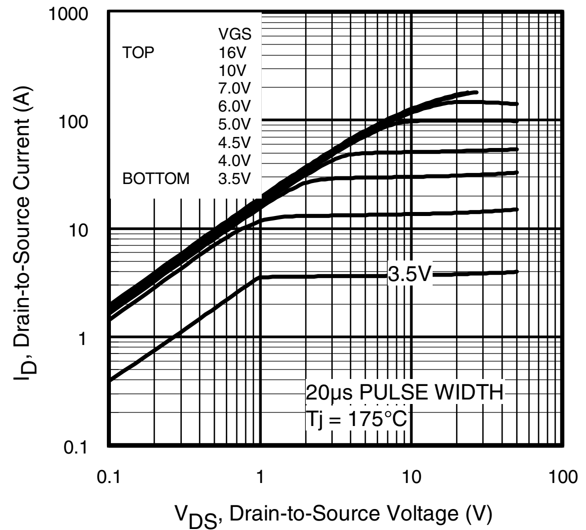


Fig 2. Typical Output Characteristics

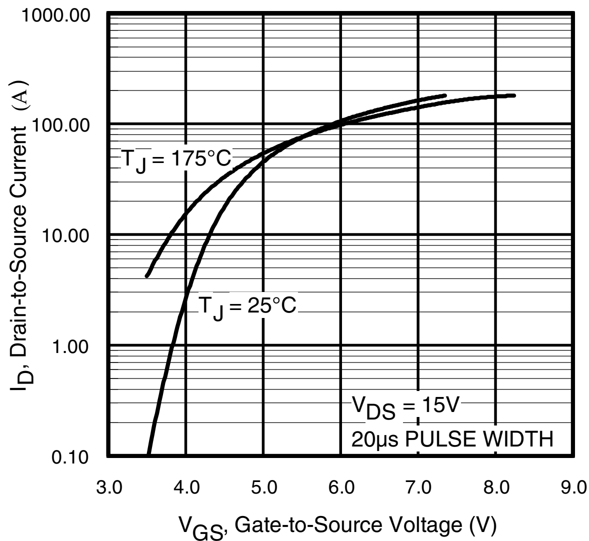


Fig 3. Typical Transfer Characteristics

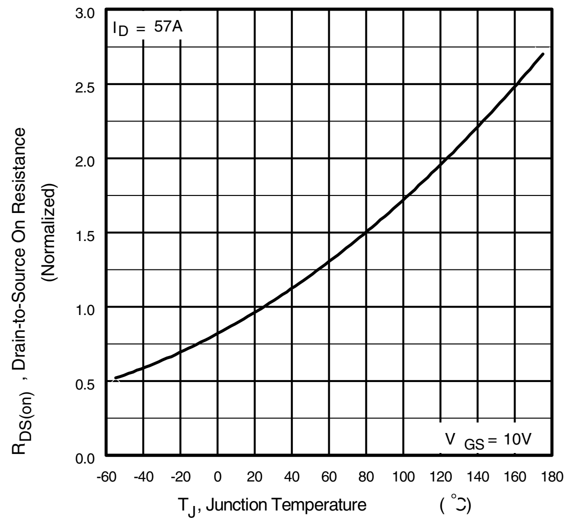


Fig 4. Normalized On-Resistance Vs. Temperature

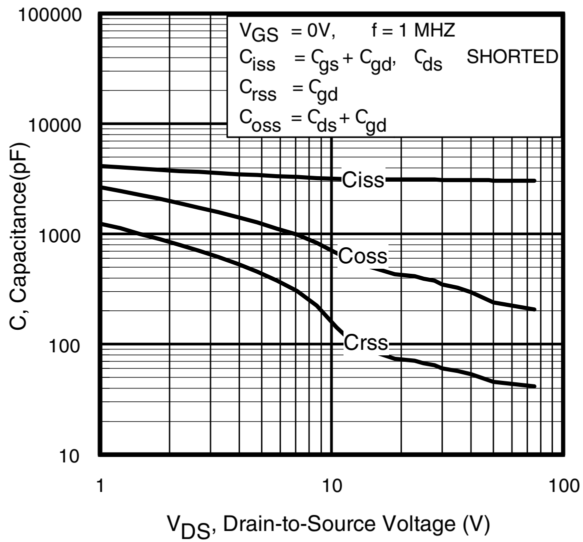


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

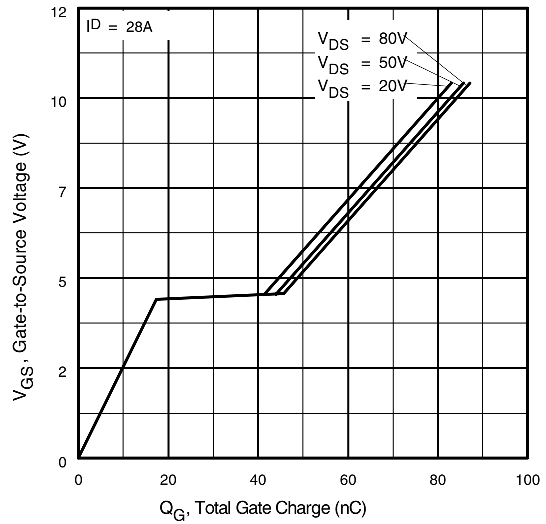


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

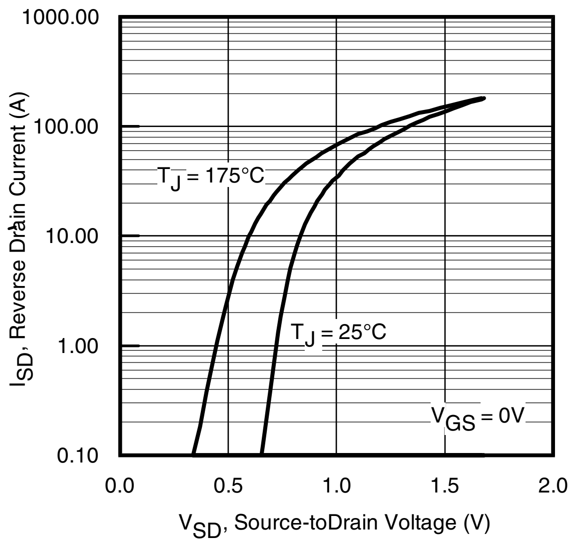


Fig 7. Typical Source-Drain Diode Forward Voltage

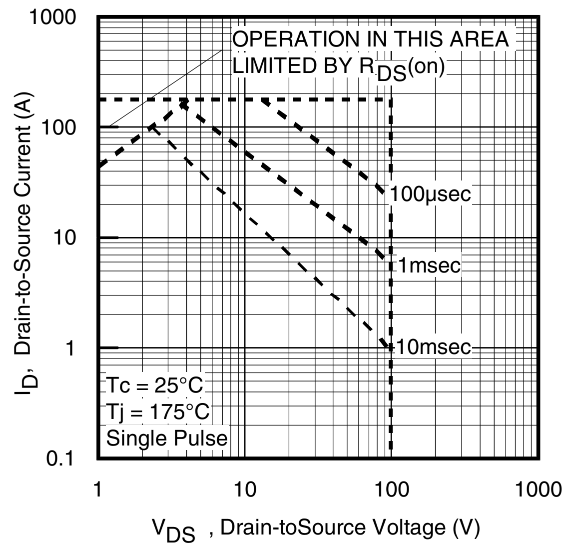


Fig 8. Maximum Safe Operating Area

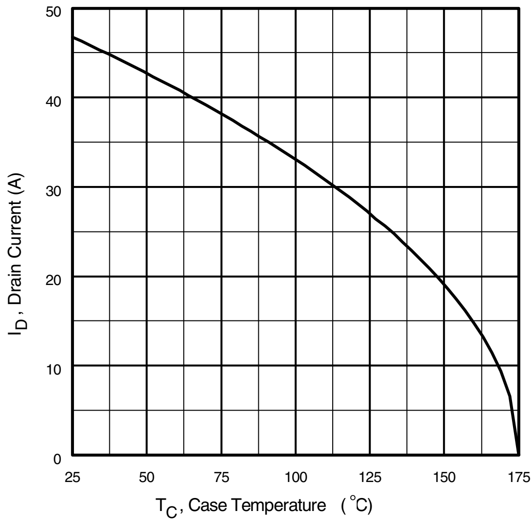


Fig 9. Maximum Drain Current Vs. Case Temperature

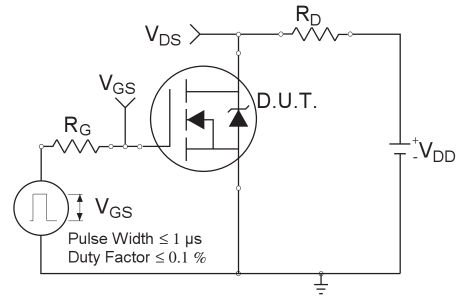


Fig 10a. Switching Time Test Circuit

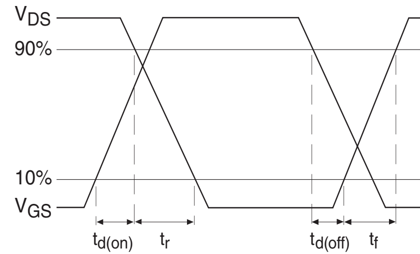


Fig 10b. Switching Time Waveforms

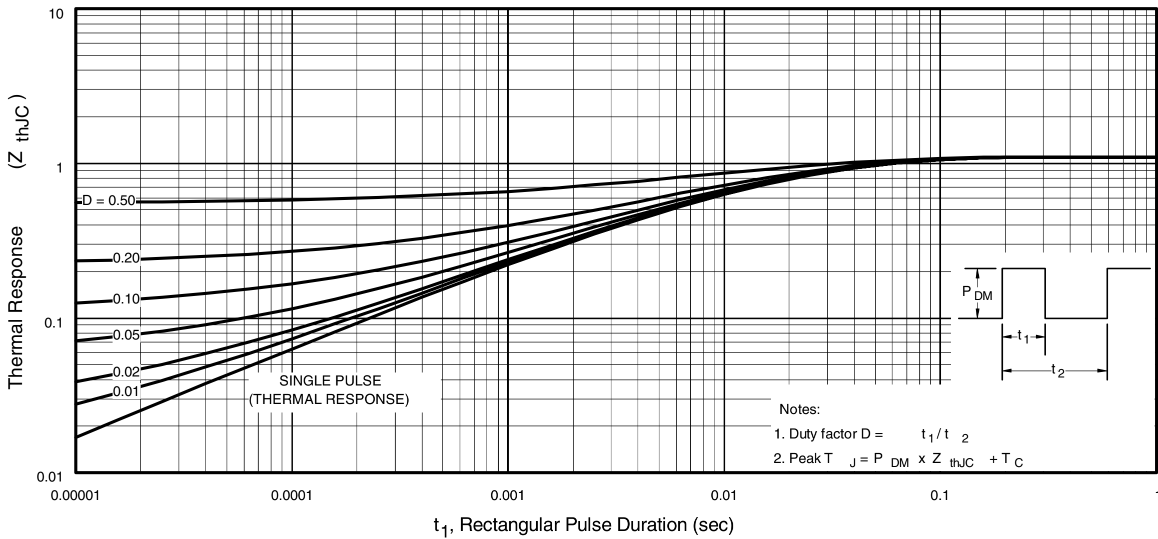


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

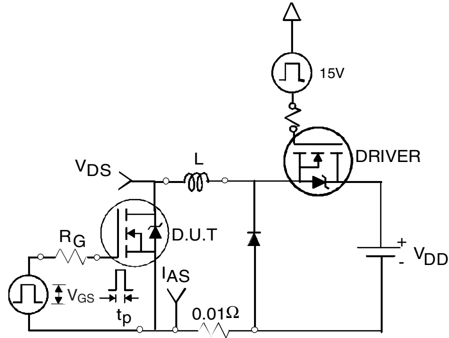


Fig 12a. Unclamped Inductive Test Circuit

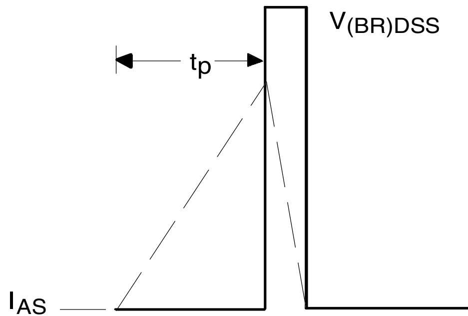


Fig 12b. Unclamped Inductive Waveforms

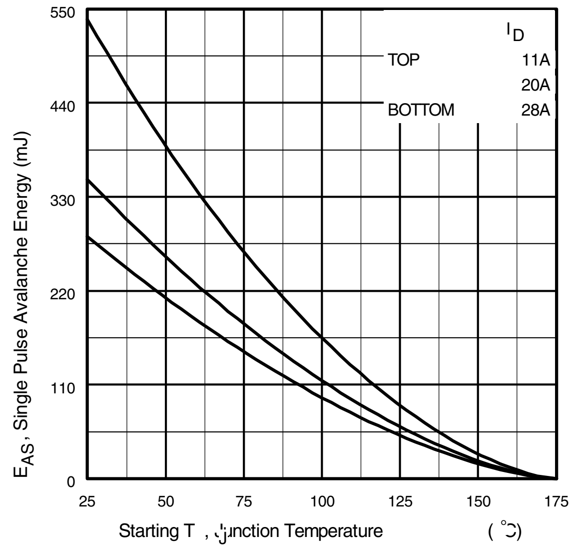


Fig 12c. Maximum Avalanche Energy
Vs. Drain Current

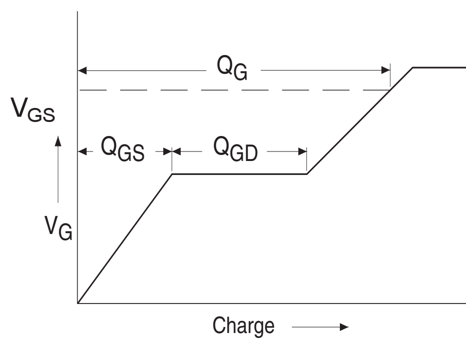


Fig 13a. Basic Gate Charge Waveform

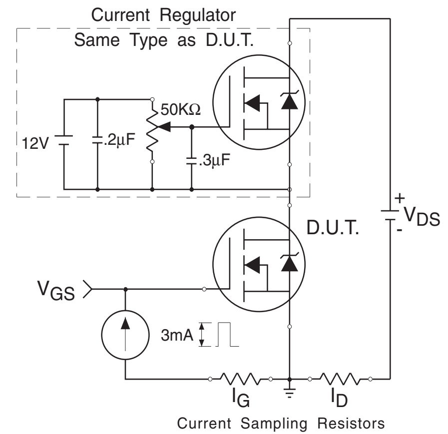
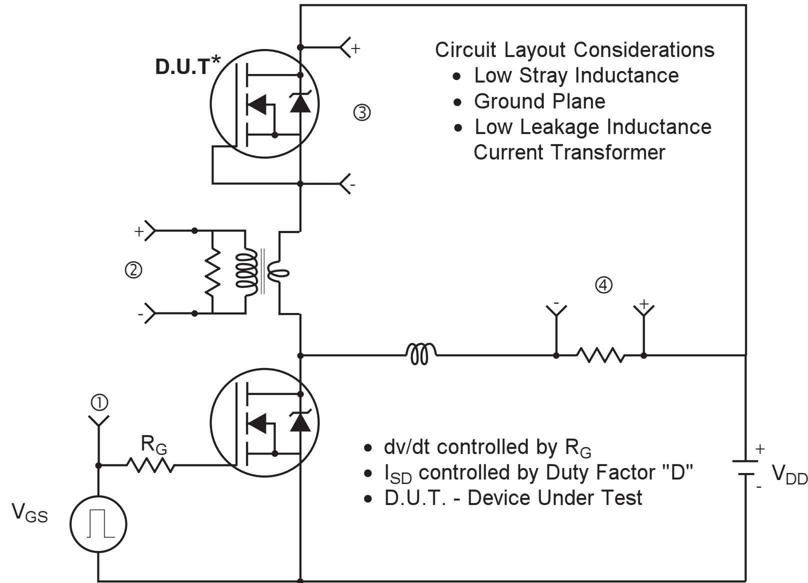
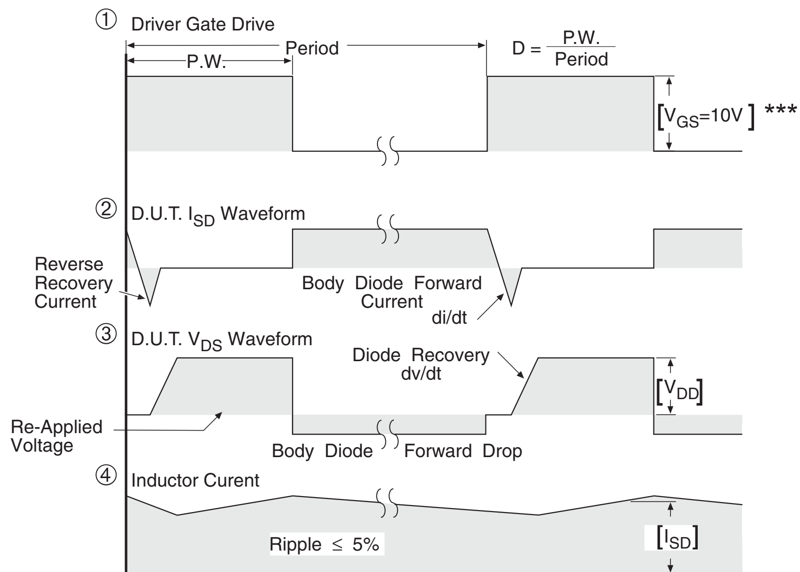


Fig 13b. Gate Charge Test Circuit

Peak Diode Recovery dv/dt Test Circuit



* Reverse Polarity of D.U.T for P-Channel

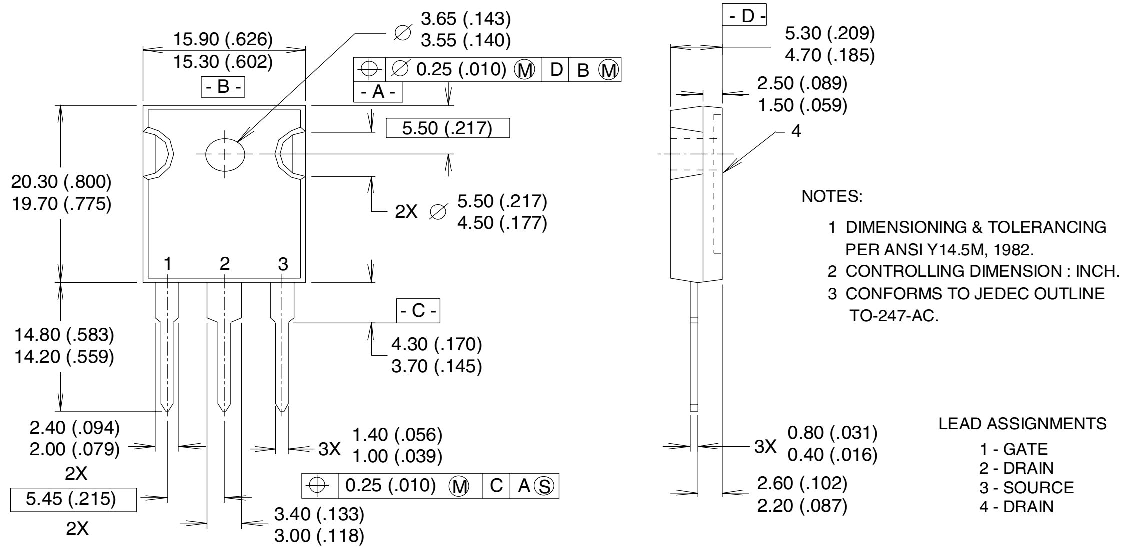


*** V_{GS} = 5.0V for Logic Level and 3V Drive Devices

Fig 14. For N-channel HEXFET® power MOSFETs

TO - 247 Package Outline

Dimensions are shown in millimeters (inches)



TO-247 package is not recommended for Surface Mount Application.

Data and specifications subject to change without notice.
This product has been designed and qualified for the Industrial market.
Qualification Standards can be found on IR's Web site.

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Note: For the most current drawings please refer to the IR website at:
http://www.irf.com/package/